

Recap

- dimensionality reduction (PCA), clustering (k-means)
- PCA : $f(x) = \mu + V\lambda$ we estimate μ and V from data.
 - $\hat{\mu} = \bar{x}$; $V =$ Eigenvector matrix of covariance matrix X
 - $X_{N \times d} \rightarrow Y_{N \times q}$ (should be a diagonal covariance matrix)

- clustering using k-means
 - assignment $\downarrow \uparrow$ \rightarrow set of templates, group assignment
 - template update

Modeling: Selection, Fitting, and Validation

selection: linear (vs) exponential model
 $y = aT + b$ (M_1)
 $= b \exp(-aT)$ (M_2) } prior knowledge, or by visual inspection

- space filling design spanning T and pH and computed reaction yield

- 1. look at the data to identify trends that can help model selection

- 2. pick a model from the class of selected models
 - hypothesis class

eg: $y = aT + b$
 $= aT + bT^2 + c$ } polynomials

pick the right polynomial

- Bayesian model selection.

two or more models: M_1, M_2, \dots

$p(x=(T, pH), y=r | M_1)$

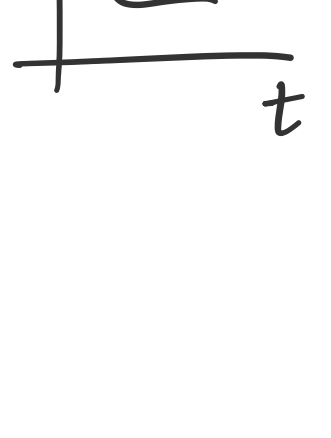
\vdots
 M_2
 \vdots

Bayes factor / simply look at likelihoods

- fitting/training: find parameters of our parametric models.

- by some form of minimization of a loss function

$L = \sum_i |y_i - f(x_i)|^2$

model  P_1, P_2, P_3, P_4
 $\Rightarrow b \exp(-at)$
 (a, b)
 $\downarrow f(P) = (a, b)$
 P
 $L = (a, b) - f(P)$

eg: thermal history of 3D printed materials

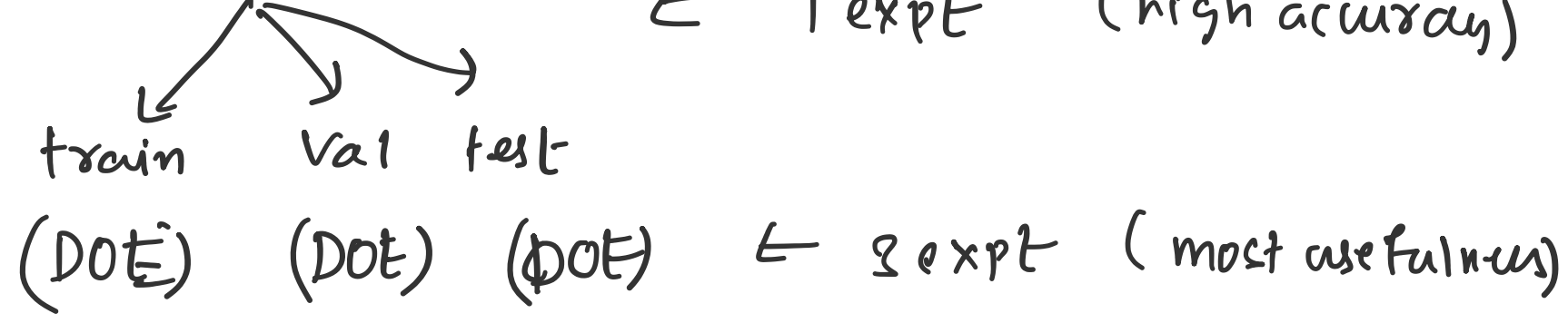
- ML and other advance techniques allows us to use arbitrary loss function, automatic diff to perform stochastic gradient descent.

- data driven modeling: universal function approximator
 $f(x) = W^T \sigma(x) + b$ - any continuous function using the deep network.

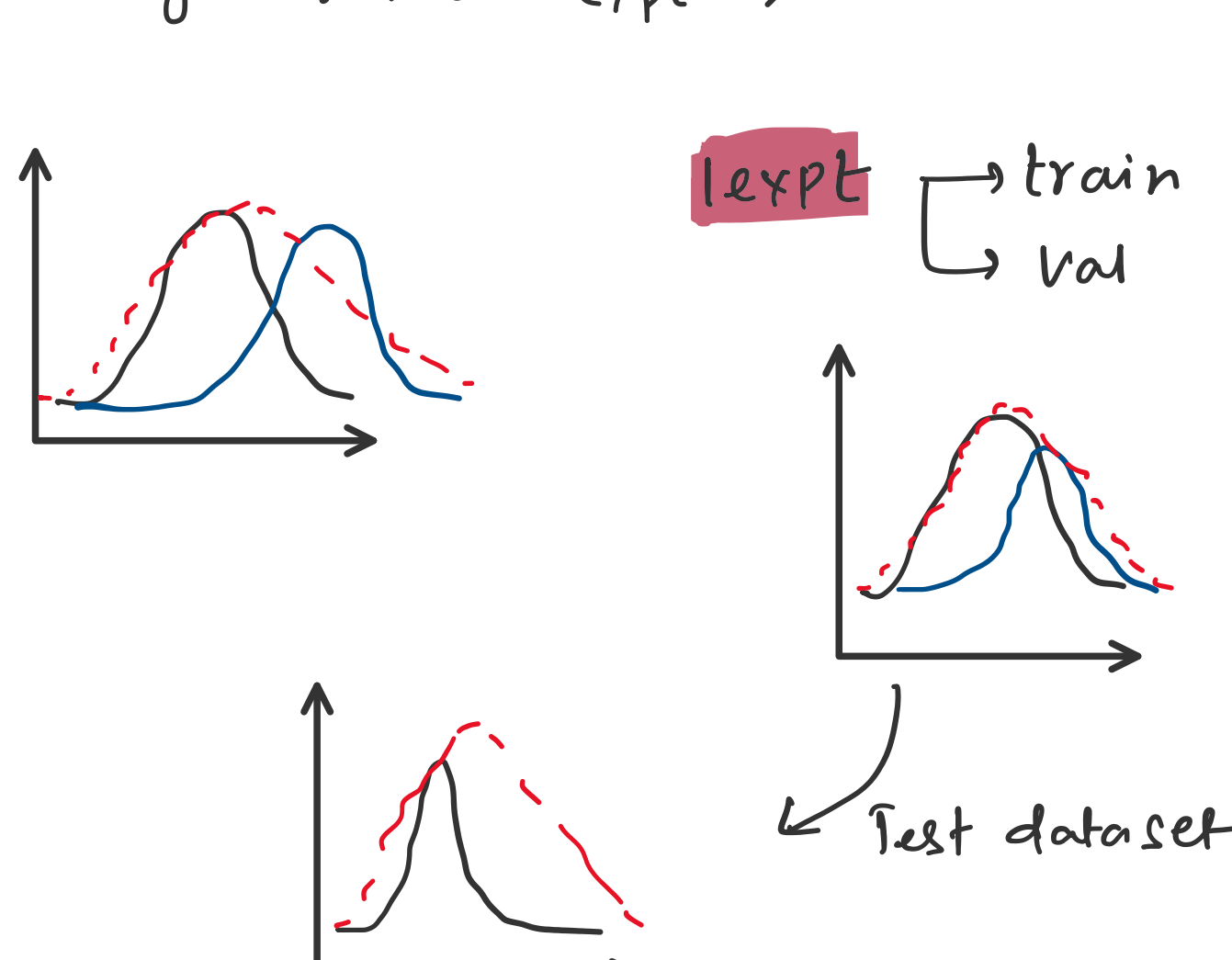
no free lunch - not every model will be able to explain the data you have.

- train data, validation data, test data.

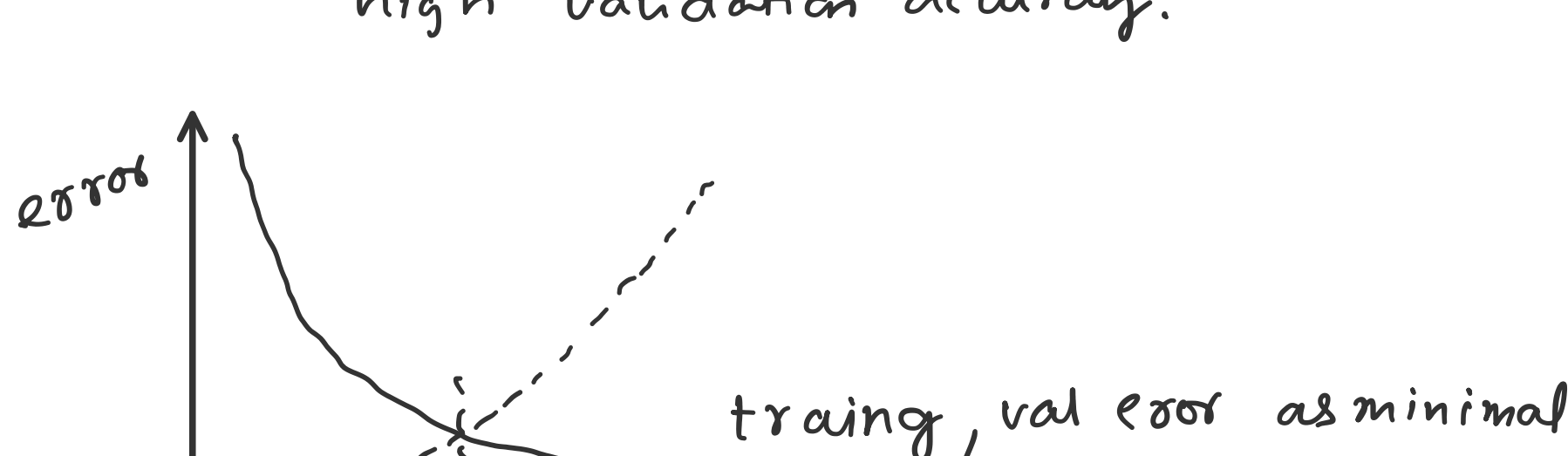
- data using any of DOE methods we discussed



every time you run an expt \rightarrow "distribution shift"



- "sweet spot" high training accuracy high validation accuracy.



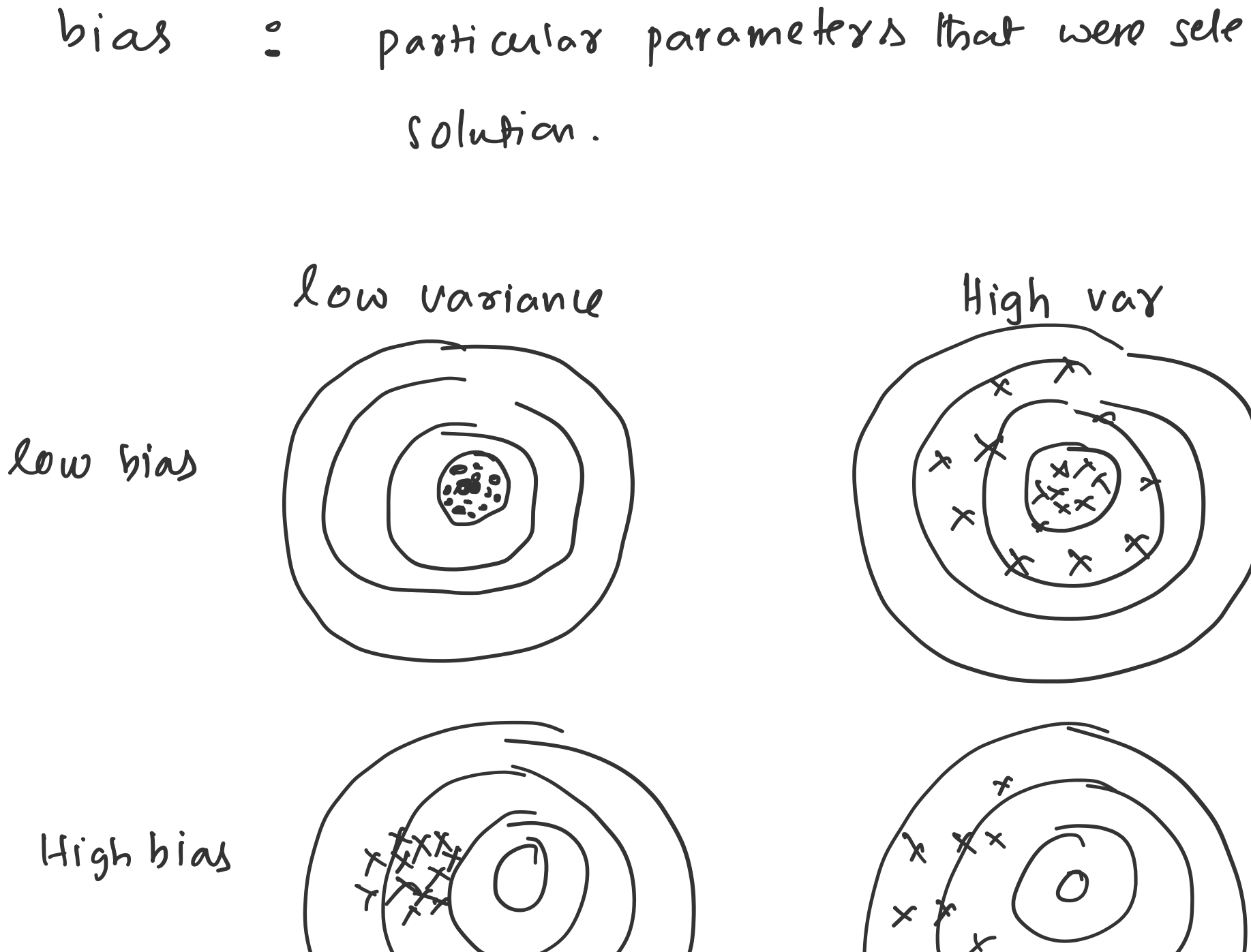
- $\gamma \rightarrow (T, pH)$

$p(T, pH) = \mu_\gamma + \epsilon \sim N(0, \sigma^2)$
 (probabilistic model)

bias, variance and noise from the data itself represent your data errors in expt that are not captured.

variance: "overspecified" your model is to the data

bias: particular parameters that were selected as solution.



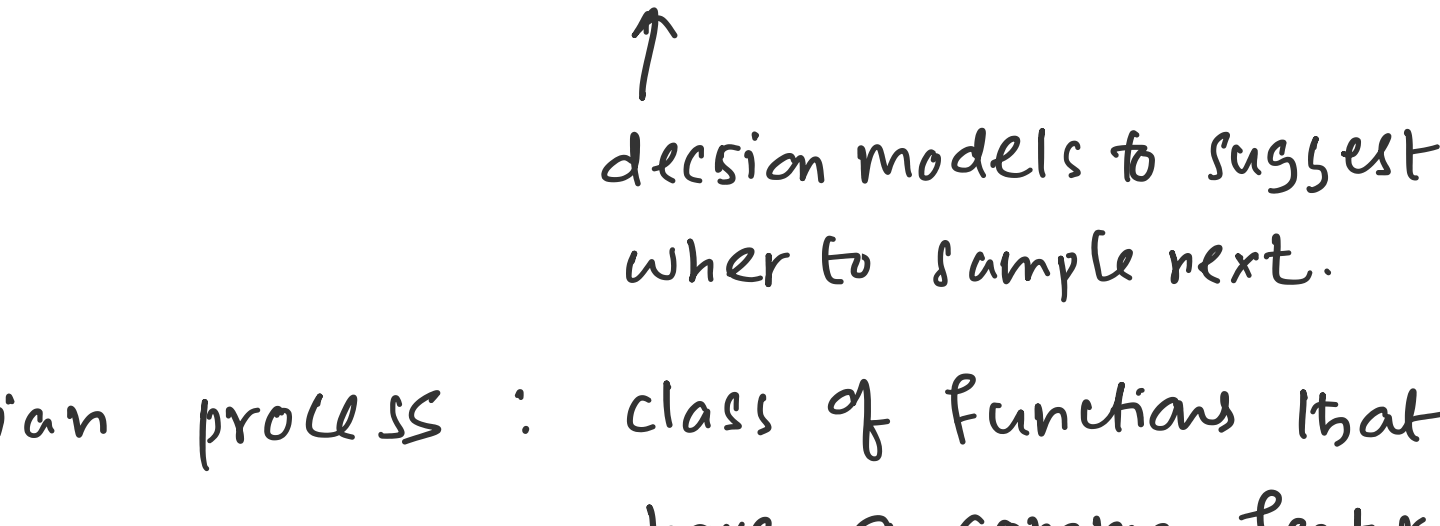
- How do we actively collect datasets: active learning (probabilistic model, decision theory), model to be accurate enough to give you the optimum: Bayesian optimization.

- prediction but also uncertainty measure.

$p(y|x) = N(\mu_y, \sigma_y^2)$

decision models to suggest when to sample next.

Gaussian process: class of functions that have a common feature in terms of continuity



\Rightarrow vector based approach \rightarrow likelihoods (MLE, MAP) fit GP